

SIS892DN-VB Datasheet N-Channel 100 V (D-S) MOSFET

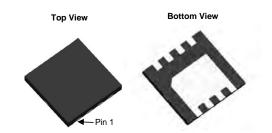
PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)			
100	0.036 at V _{GS} = 10 V	21	23 nC			
100	0.0375 at V _{GS} = 8 V	17	23110			

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Extremely Low Q_{gd} for Switching Losses
- 100 % R_g Tested
- 100 % Avalanche Tested
- Compliant to RoHS Directive 2002/95/EC

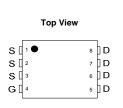


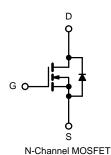
DFN 3x3 EP



APPLICATIONS

· Primary Side Switch





ABSOLUTE MAXIMUM RATINGS (T _A = 25 °C, unless otherwise noted)						
Parameter		Symbol	Limit	Unit		
Drain-Source Voltage		V_{DS}	100	V		
Gate-Source Voltage		V_{GS}	± 20			
	T _C = 25 °C		21			
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C] [17			
Continuous Diain Current (1) = 150 °C)	T _A = 25 °C	I _D	15 ^{b, c}			
	T _A = 70 °C]	13 ^{b, c}	A		
Pulsed Drain Current		I _{DM}	50			
Continuous Source-Drain Diode Current	T _C = 25 °C		4.5			
Continuous Source-Diam Diode Current	T _A = 25 °C	I _S	2.6 ^{b, c}			
Single Pulse Avalanche Current Single Pulse Avalanche Energy L = 0.1 mH		I _{AS}	20			
		E _{AS}	20	mJ		
	T _C = 25 °C		5.9			
Maximum Power Dissipation	T _C = 70 °C	р 1	3.8	W		
Maximum Fower Dissipation	T _A = 25 °C	- P _D	3.1 ^{b, c}	VV		
	T _A = 70 °C]	2 ^{b, c}			
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C		

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{b, f}	t ≤ 10 s	R _{thJA}	33	40	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	17	21	0,7	

Notes:

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under steady state conditions is 80 °C/W.



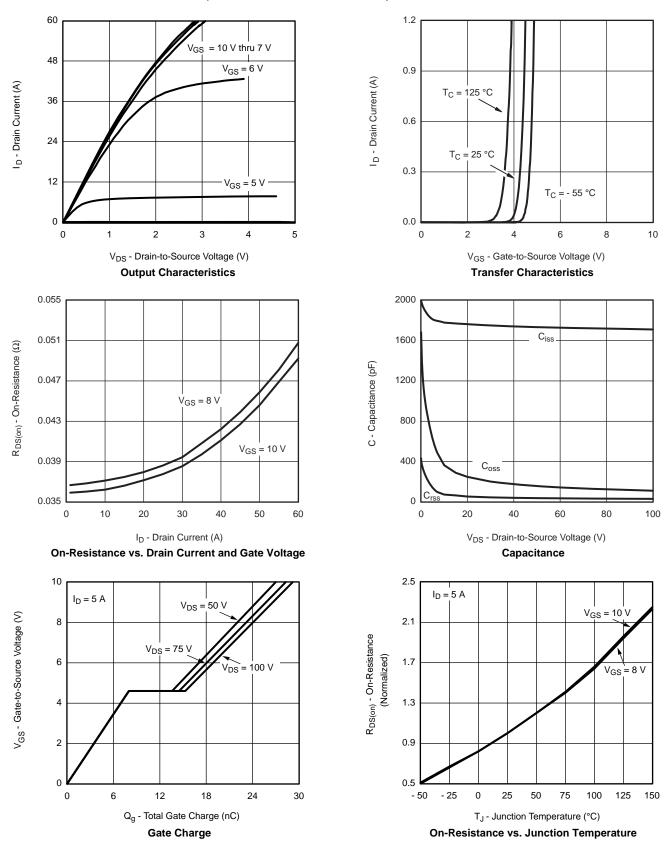
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static				•		,
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			172		>//00
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	$I_D = 250 \mu A$		- 10		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_{D} = 250 \mu\text{A}$	2.5		4.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
7 0 1 1/1 5 1 0 1		V _{DS} = 100 V, V _{GS} = 0 V			1	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 100 V, V _{GS} = 0 V, T _J = 55 °C			10	μΑ
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α
Dania Osama Os Otata Basistana	_ ` ′	V _{GS} = 10 V, I _D = 5 A		0.036		
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 8 \text{ V}, I_{D} = 5 \text{ A}$		0.0375		Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 5 A		23		S
Dynamic ^b				<u> </u>		•
Input Capacitance	C _{iss}			1735		
Output Capacitance	C _{oss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		160		pF
Reverse Transfer Capacitance	C _{rss}			37		
Total Gate Charge	Q _g	$V_{DS} = 75 \text{ V}, V_{GS} = 10 \text{ V}, I_{D} = 5 \text{ A}$	28.	28.5	43	nC
		_		23	35	
Gate-Source Charge	Q_{gs}	$V_{DS} = 75 \text{ V}, V_{GS} = 8 \text{ V}, I_{D} = 5 \text{ A}$		8		
Gate-Drain Charge	Q _{gd}			6.5		
Gate Resistance	R _g	f = 1 MHz		0.85	1.3	Ω
Turn-on Delay Time	t _{d(on)}			14	21	
Rise Time	t _r	V_{DD} = 50 V, R_L = 10 Ω		12	18	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		22	33	
Fall Time	t _f			6	10	no
Turn-On Delay Time	t _{d(on)}			16	24	ns -
Rise Time	t _r	V_{DD} = 50 V, R_L = 10 Ω		12	18	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 8 \text{ V}, R_g = 1 \Omega$		20	30	
Fall Time	t _f			7	12	
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			7.7	Α
Pulse Diode Forward Current ^a	I _{SM}				50	^
Body Diode Voltage	V _{SD}	I _S = 2.6 A		0.77	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			63	95	ns
Body Diode Reverse Recovery Charge	Q _{rr}	L = 5 A dl/dt = 100 A/up T = 25 °C		110	165	nC
Reverse Recovery Fall Time	t _a	$I_F = 5 \text{ A, dI/dt} = 100 \text{ A/}\mu\text{s, T}_J = 25 \text{ °C}$		49		ns
Reverse Recovery Rise Time	t _b			14		

Notes:

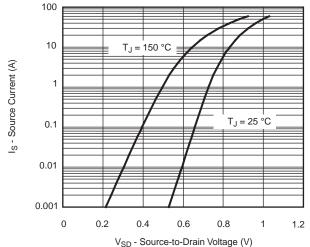
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- a. Guaranteed by design, not subject to production testing.

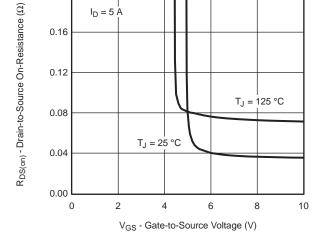
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.





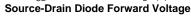


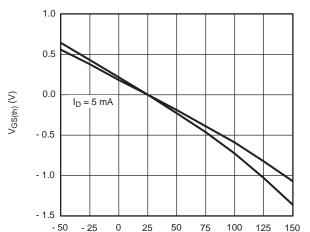




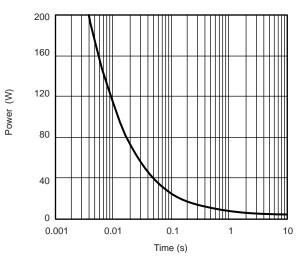
0.20

 $I_D = 5 \text{ A}$



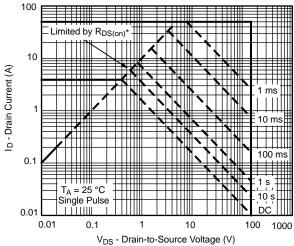


On-Resistance vs. Gate-to-Source Voltage



T_J - Temperature (°C) **Threshold Voltage**

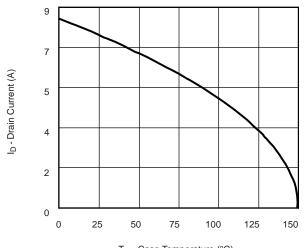
Single Pulse Power, Junction-to-Ambient



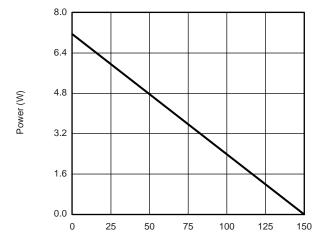
* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

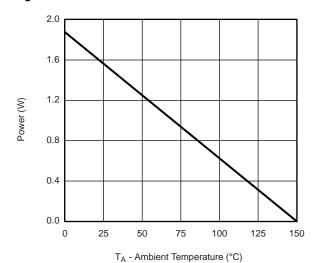
Safe Operating Area, Junction-to-Ambient





T_C - Case Temperature (°C) Current Derating*





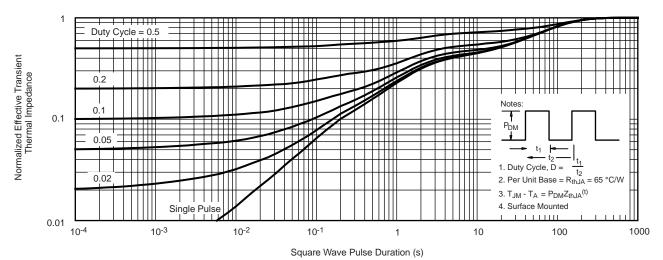
Power, Junction-to-Ambient

Power, Junction-to-Case

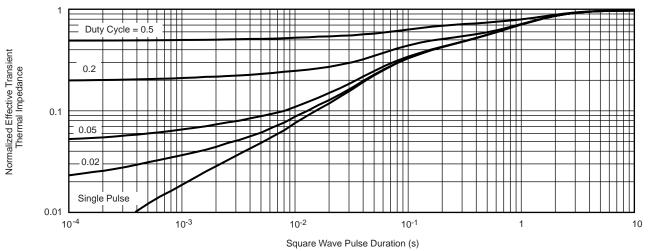
T_C - Case Temperature (°C)

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.



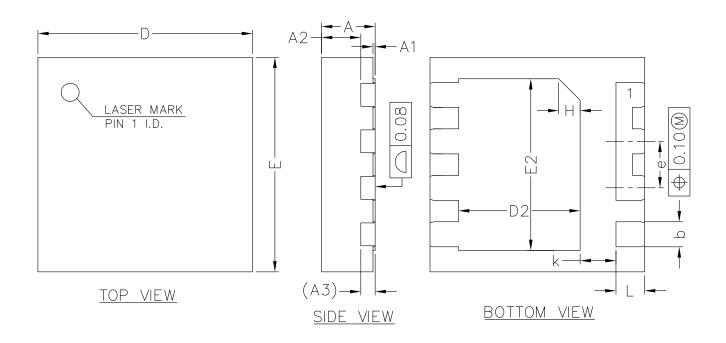


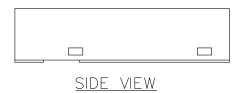
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot







COMMON DIMENSIONS (UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX	
А	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
A2	0.50	0.55	0.60	
А3	0.20REF			
b	0.30	0.35	0.40	
D	2.90	3.00	3.10	
E	2.90	3.00	3.10	
D2	1.60	1.70	1.80	
E2	2.30	2.40	2.50	
е	0.55	0.65	0.75	
K	0.40	0.50	0.60	
L	0.35	0.40	0.45	



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